SN54ABT16843 . . . WD PACKAGE

SCBS223E - OCTOBER 1992 - REVISED MAY 1997

- Members of the Texas Instruments *Widebus*™ Family
- State-of-the-Art *EPIC-*II*B*[™] BiCMOS Design Significantly Reduces Power Dissipation
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- High-Impedance State During Power Up and Power Down
- High-Drive Outputs (–32-mA I_{OH}, 64-mA I_{OL})
- Package Options Include Plastic Thin Shrink Small-Outline (DGG), 300-mil Shrink Small-Outline (DL) Packages and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings

description

The 'ABT16843 18-bit bus-interface D-type latches are designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

The 'ABT16843 can be used as two 9-bit latches or one 18-bit latch. The 18 latches are transparent D-type latches. The device provides true data at its outputs.

A buffered output-enable (\overline{OE}) input can be used to place the nine outputs in either a normal logic state (high or low logic levels) or a high-impedance state. The outputs are in the high-impedance state during power up and power down. The outputs remain in the high-impedance state while the device is powered down. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without need for interface or pullup components.

SN74ABT16843 DGG OR DL PACKAGE (TOP VIEW)								
1CLR 1OE 1Q1 GND 1Q2 1Q3 1Q3 Vcc 1Q4 1Q5 1Q6 GND 1Q7 1Q8 1Q7 2Q1 2Q2 2Q3 GND 2Q4 2Q5	(TOP VII 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 20	EW) 56 1 1LE 55 1 1PRE 54 1 1D1 53 GND 52 1 1D2 51 1 1D3 50 V _{CC} 49 1 1D4 48 1 1D5 47 1 1D6 46 GND 45 1 1D7 44 1 1D8 43 1 1D9 42 2 D1 41 2 D2 40 2 D3 39 GND 38 2 D4 37 2 D5						
2Q5 [2Q6 [20 21	37 2D5 36 2D6						
V _{CC} 2Q7 2Q8	24	35 V _{CC} 34 2D7 33 2D8						
GND [2Q9 [2OE [2CLR [32 GND 31 2D9 30 2PRE 29 2LE						



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description (continued)

OE does not affect the internal operations of the latch. Previously stored data can be retained or new data can be entered while the outputs are in the high-impedance state.

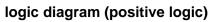
When V_{CC} is between 0 and 2.1 V, the device is in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 2.1 V, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

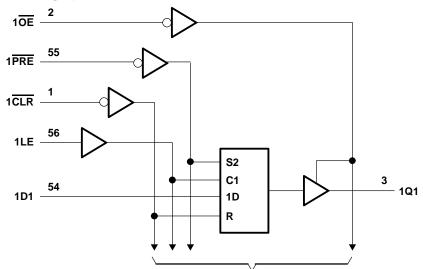
The SN54ABT16843 is characterized for operation over the full military temperature range of -55° C to 125° C. The SN74ABT16843 is characterized for operation from -40° C to 85° C.

FUNCTION TABLE (each 9-bit latch)									
		INPUTS			OUTPUT				
PRE	CLR	Q							
L	Х	L	Х	Х	н				
н	L	L	Х	Х	L				
н	Н	L	Н	L	L				
н	н	L	н	Н	н				
н	Н	L	L	Х	Q ₀				
Х	Х	Н	Х	Х	Z				

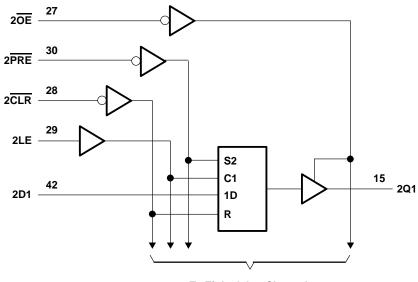


SN54ABT16843, SN74ABT16843 **18-BIT BUS-INTERFACE D-TYPE LATCHES** WITH 3-STATE OUTPUTS SCBS223E – OCTOBER 1992 – REVISED MAY 1997





To Eight Other Channels



To Eight Other Channels



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC} Input voltage range, V _I (see Note 1) Voltage range applied to any output in the high or power-off state, V _O Current into any output in the low state, I _O : SN54ABT16843 SN74ABT16843	0.5 V to 7 V 0.5 V to 5.5 V
Input clamp current, I _{IK} (V _I < 0)	
Output clamp current, I _{OK} (V _O < 0)	
Package thermal impedance, θ_{JA} (see Note 2): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T _{stg}	–65°C to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.

recommended operating conditions (see Note 3)

					SN74ABT16843		UNIT
			MIN	MAX	MIN	MAX	UNIT
VCC	Supply voltage	4.5	5.5	4.5	5.5	V	
VIH	High-level input voltage	2	M	2		V	
VIL	Low-level input voltage		0.8		0.8	V	
VI	Input voltage	0	Vcc	0	VCC	V	
ЮН	High-level output current		1	-24		-32	mA
I _{OL}	Low-level output current		ru _c	48		64	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	Outputs enabled	701	10		10	ns/V
Δt/ΔV _{CC}	Power-up ramp rate		Q 200		200		μs/V
TA	Operating free-air temperature		-55	125	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		Т	A = 25°C	;	SN54AB	T16843	SN74ABT16843		UNIT	
				MIN	TYP†	MAX	MIN	MAX	MIN	MAX	UNIT	
VIK		V _{CC} = 4.5 V,	lj = -18 mA			-1.2		-1.2		-1.2	V	
		V _{CC} = 4.5 V,	I _{OH} = -3 mA	2.5			2.5		2.5			
Val		V _{CC} = 5 V,	$I_{OH} = -3 \text{ mA}$	3			3		3	3		
VOH		V _{CC} = 4.5 V	I _{OH} = -24 mA	2			2		V		v	
		VCC = 4.5 V	$I_{OH} = -32 \text{ mA}$	2*					2			
VOL		V _{CC} = 4.5 V	I _{OL} = 48 mA			0.55		0.55			v	
VOL		VCC = 4.5 V	I _{OL} = 64 mA			0.55*				0.55	v	
V _{hys}					100						mV	
lj		$V_{CC} = 0$ to 5.5 $V_{I} = V_{CC}$ or GN				±1		±1		±1	μΑ	
IOZPU	‡	$V_{CC} = 0 \text{ to } 2.1$ $V_{O} = 0.5 \text{ V to } 2$	V, 7 V, OE = X			±50		±50		±50	μΑ	
IOZPD	‡	$V_{CC} = 2.1 \text{ V to}$ $V_{O} = 0.5 \text{ V to } 2$	0, .7 V, OE = X			±50	277	±50		±50	μΑ	
IOZH		$V_{CC} = 2.1 \text{ V}$ to $V_{O} = 2.7 \text{ V}$, $\overline{\text{OE}}$				10	DODU	10		10	μA	
I _{OZL}		$V_{CC} = 2.1 \text{ V}$ to $V_{O} = 0.5 \text{ V}$, OE	5.5 V, ≥ 2 V			-10	Q	-10		-10	μΑ	
loff		V _{CC} = 0,	V _I or V _O \leq 4.5 V			±100				±100	μA	
ICEX	Outputs high	V _{CC} = 5.5 V,	Vo = 5.5 V			50		50		50	μA	
١٥		V _{CC} = 5.5 V,	V _O = 2.5 V	-50	-100	-180	-50	-180	-50	-180	mA	
	Outputs high	.,				0.5		0.5		0.5		
ICC	Outputs low	V _{CC} = 5.5 V, I _O = 0, V _I = V _{CC} or GND				85		85		85	mA	
	Outputs disabled					0.5		0.5		0.5		
∆ICC¶		$V_{CC} = 5.5 V, O$ Other inputs at	ne input at 3.4 V, V _{CC} or GND			1.5		1.5		1.5	mA	
Ci		V _I = 2.5 V or 0.	5 V		3.5						pF	
Co		V _O = 2.5 V or 0	0.5 V		8						pF	

* On products compliant to MIL-PRF-38535, this parameter does not apply.

[†] All typical values are at V_{CC} = 5 V.

[‡] This parameter is characterized, but not production tested.

§ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

 \P This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.



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timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

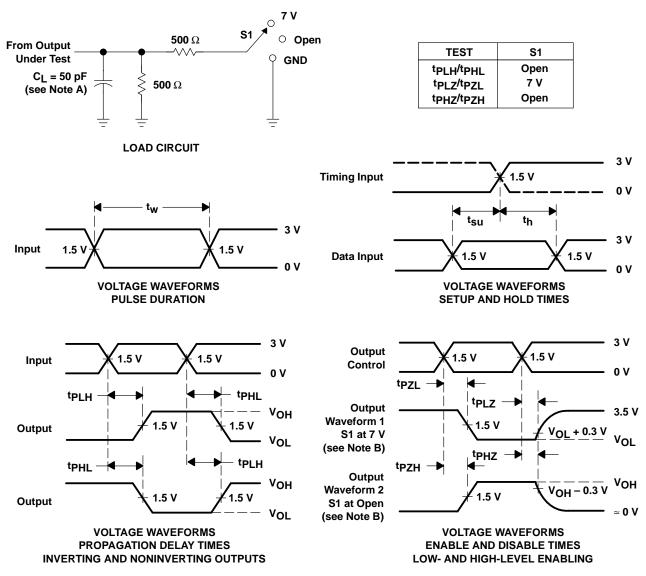
				= 5 V, 25°C	SN54ABT16843		SN74ABT16843		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
t _w Pulse duration	CLR low	3.3		3.3	Ņ	3.3			
	PRE low	3.3		3.3	VIE	3.3		ns	
		LE high	3.3		3.3	N.F	3.3		
	Setup time, data before LE \downarrow	High	0.9		0.9	2	0.9		ns
t _{su}		Low	0.6		0.6		0.6		115
t lold time date after L	Hold time, data after LE↓	High	1.7		Q1.7		1.7		ns
^t h		Low	1.8		Q 1.8		1.8		115

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 5 V, T _A = 25°C			SN54ABT16843		SN74ABT16843		UNIT
		(001101)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
^t PLH	D	Q	1.6	3.1	4.2	1.6	5.1	1.6	4.8	ns
^t PHL	D	y	1.6	3.2	4.2	1.6	5	1.6	4.8	115
^t PLH	LE	Q	2.3	4	5	2.3	6.3	2.3	5.9	ns
^t PHL		Ŷ	2.5	3.9	4.8	2.5	5.6	2.5	5.3	115
^t PLH	PRE	Q	2.1	4	5.1	2.1	6.3	2.1	6.1	ns
^t PHL	PRE	8	2.2	3.7	4.6	2.2	5.3	2.2	5	115
^t PLH	CLR	Q	1.9	3.7	4.8	1.9	5.7	1.9	5.4	ns
^t PHL	CLR	y	2.2	4.2	5.3	2.2	6.1	2.2	6	115
^t PZH	OE	Q	1.6	3.3	4.3	X 1.6	5.5	1.6	5.4	
^t PZL	OE	Ŷ	2	3.2	4.6	2	5.9	2	5.8	ns
^t PHZ	OE	Q	1.7	4	5.5	1.7	6.4	1.7	6.3	
^t PLZ	0E	Ŷ	1.7	3.7	4.4	1.7	5.3	1.7	5.2	ns



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PARAMETER MEASUREMENT INFORMATION

NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f \leq 2.5 ns, t_f \leq 2.5 ns.

D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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